Substitute for form 1449A/PTO

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 2

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Application Number	09/610,889	
Filing Date	July 6, 2000	
First Named Inventor	FINAROV et al.	
Group Art Unit	2877	
Examiner Name		
Attorney Docket Number	FINAROV=3	

				U.S. PATENT DOCU	MENTS	
Examiner Initials*	Cite No.1	U.S. Patent Number	Document Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	4,905,170		FOROUHI et al.	Feb. 27, 1990	
	AB	5,361,137		ATON et al.	Nov. 1, 1994	
	AC	4,330,213		KLEINKNECHT et al.	May 18, 1982	
	AD	5,703,692		MC NEIL et al.	Dec. 30, 1997	
	AE	5,889,593		BAREKET	March 30, 1999	
	AF	4,999,014		GOLD et al.	March 12, 1991	
	AG	5,164,790		MC NEIL et al.	Nov. 17, 1992	
	AH	4,710,642		MCNEIL	Dec. 1, 1987	
	Al	5,867,276		MCNEIL et al.	Feb. 2, 1999	
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				FORE	IGN PATENT DOCUMEN	TS		
			Foreign Patent Nu	mber	Name of Detector as A - 1'	Date of Publication	Pages, Columns, Lines,	Г
Examiner nitials*	Cite No. <sup>1</sup>	Office <sup>3</sup>	Number	Kind Code (if known)	of Cited Document	of Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	7
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<sup>\*</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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				Application Number	09/610,889	·	
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STATEMENT BY APPLICANT				First Named Inventor	FINAROV et al.	<del></del>	
				Group Art Unit	2877		
	(use as many	sheets as n	ecessary)	Examiner Name	<del> </del>	<del></del>	
Sheet	2	of	2	Attorney Docket Number	FINAROV=3		

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T²
•	AJ	VOSKOVTSOVA et al., Soviet Journal of Optical Technology, (1993) vol.60, no.9, pp.617-619	
	AK	ROGER et al, "Inverse scattering method in electromagnetic optics: Applications to diffraction grating", <u>J. Opt. Soc. Am.</u> , (1980), vol.70, No. 12, pp.1483-1495, Optical Society of America	
	AL	ROGER et al., "The perfectly conducting grating from the point of view of inverse diffraction", Optica Acta, (1979), vol.26, No. 4, pp.447-460, Taylor & Francis Ltd.	
	AM	ROGER et al., "Grating Profile Reconstruction by an Inverse Scattering Method" Optics Communication, (1980), vol.35, No.3, pp.299-302	
	AN	LOCHBIHLER et al., "Reconstruction of the profile of gold wire gratings: A comparison of different methods", Optik, (1994), vol.98, No.1, pp.21-25, Germany	
	AO	SAVITSKII et al., "Efficiency optimization of reflecting diffraction gratings with a trapezoidal groove profile", Opt. Spectrosc, (1985), vol.59, No.2, pp.251-254, The Optical Society of America	
	AP	SPIKHAL'SKII, "Radiative Bragg Mirrors: Spectral Characteristics Versus Grating Groove Profile", Optics Communication, (1986), vol.57, No. 6, pp.375-379, Holland	
	AQ	NAQVI et al., "Etch depth estimation of large-period silicon grating will multivariate calibration of rigorously simulated diffraction profile", <u>Journal of the Optical Society of America</u> , (1994), vol.11, No.9, pp.2485-2493, Optical Society of America	
	AR	MOHARAM et al., "Rigorous coupled-wave analysis of planar-grating diffraction", <u>Journal of the Optical Society of America,</u> (1981), vol.71, No. 7, pp.811-818, Optical Society of America	
	AS	RAYMOND et al., "Resist and etched line profile characterization using scatterometry", <u>SPIE</u> , (1997), vol.3050, pp.476-486	

Examiner	Date	
Signature	Considered	
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<sup>\*</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

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(use as many sheets as necessary)

of 1

Complete if Known					
Application Number					
Filing Date	July 6, 2000				
First Named Inventor	Moshe FINAROV				
Group Art Unit	2877				
Examiner Name					
Attorney Docket Number	FINAROV=3				

	U.S. PATENT DOCUMENTS								
Examiner Initials*	Cite No: <sup>1</sup>	U.S. Patent Number	Document Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
	AU	6,045,433		DVIR et al.	04-04-2000	-			
	AV	5,682,242		EYLON	10-28-1997				
	AW	5,867,590		EYLON	02-02-1999				
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			Foreign Patent Nu	mber	Name of Patentee or Applicant	Date of Publication	Pages, Columns, Lines,			
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1	Examiner		Date	
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